

Search Notes

Application/Control No.

10/532,436

Examiner

Dinh Q. Nguyen

Applicant(s)/Patent under
Reexamination

ZITTEL ET AL.

Art Unit

3752

SEARCHED

Class	Subclass	Date	Examiner
239	112		
	117		
	414		
	413		
	415		
	240		
	292	1/02/08	DSW
222	145-5		
	145-7		
	145-2		
	135	1/07/08	DSW

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
<i>PATENT SEARCH ATTACHED</i>	1/07/08	DSW

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner